

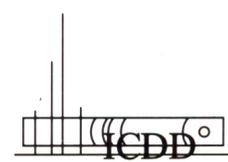


Powder Diffraction

An international journal of materials characterization

Volume 13 Number 1 March 1998

33-1161									
SiO ₂									
Silicon Oxide									
Quartz, syn									
Rad. CuKα ₁	λ 1.540598	Filter Mono.	d-sp Diff.	dÅ	Int	hkℓ	dÅ	Int	hkℓ
Cut off	Int. Diffractometer		W _{max} 3.6	4.257	22	100	1.1532	1	311
Ref. Natl. Bur. Stand. (U.S.) Monogr. 25, 18 61 (1981)				3.342	100	101	1.1405	<1	204
				2.457	8	110	1.1143	<1	303
				2.282	8	102	1.0813	2	312
				2.237	4	111	1.0635	<1	400
				2.127	6	200	1.0476	1	105
				1.9792	4	201	1.0347	<1	401
				1.8179	14	112	1.0438	<1	214
				1.8021	<1	003	1.0347	<1	223
				1.6719	4	202	1.0150	<1	214
				1.6591	2	103	0.9898	1	313
				1.6082	<1	210	0.9873	1	313
				1.4536	9	211	0.9783	<1	304
				1.4189	1	113	0.9762	<1	320
				1.3820	<1	300	0.9636	<1	205
				1.3752	6	212			
				1.3718	7	203			
				1.2880	8	301			
				1.2558	2	104			
				1.2285	2	302			
				1.1999	1	220			
				1.1978	2	213			
				1.1843	1	221			
				1.1804	3	311			
					3	312			
S.G. P3 ₂ 21 (154)	A	C	1.1001						
c 5.4053(4)	Z	3	mp						
Ref. Swanson, Fuyat, Natl. Bur. Stand. (U.S.), Circ. 539, 3 24 (1954)									
Colorless									
Pattern taken at 25 C. Sample from the Glass Section at NBS.									
Gaithersburg, Maryland, USA. Ground single-crystals of optical quality.									
University, Fargo, North Dakota, USA. McCarty, G., North Dakota State									
Quartz group. Also called: silica. Also called: low quartz. Silica used									
as internal standard. PSC: hP9. To replace 5-490 and validated by cal-									
culated pattern. Plus 6 additional reflections to 0.9089.									





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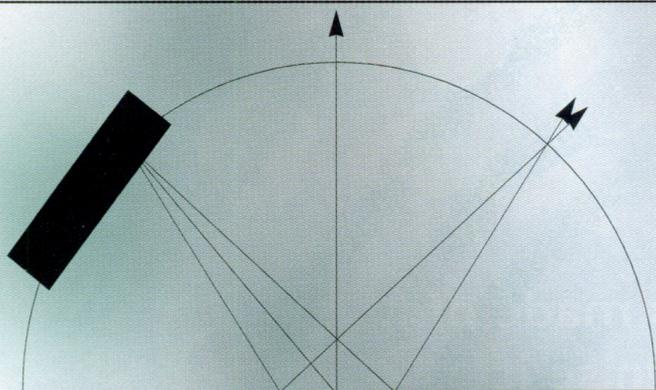
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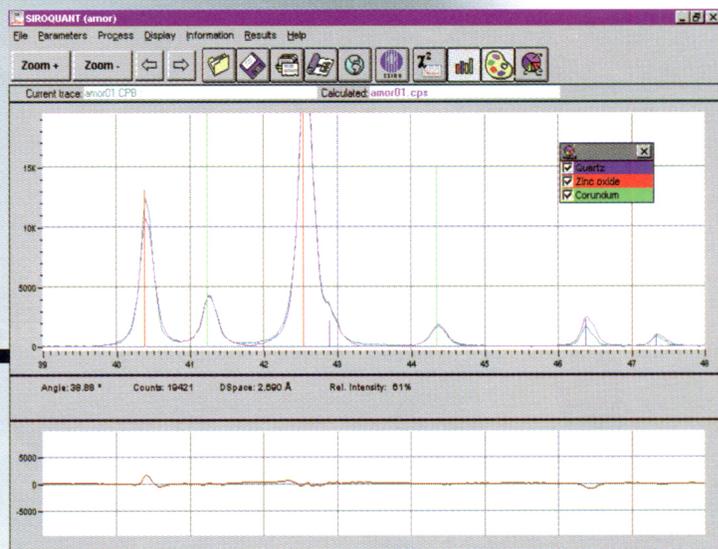
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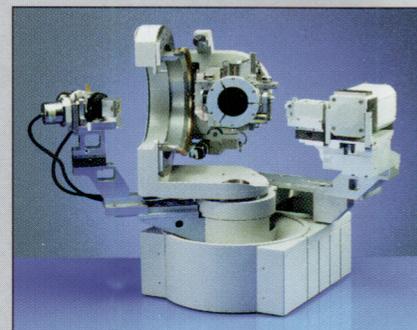


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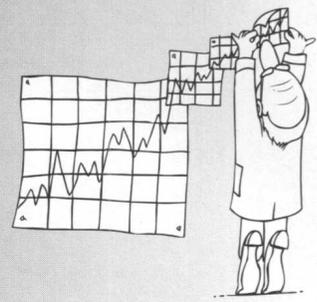
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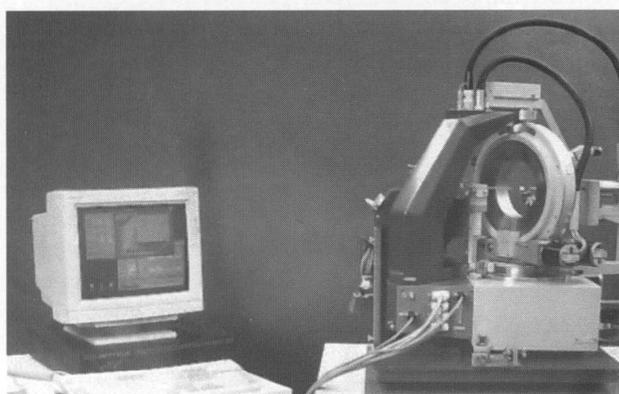
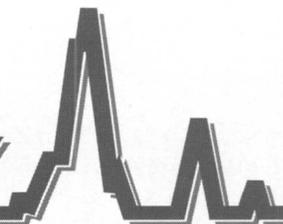
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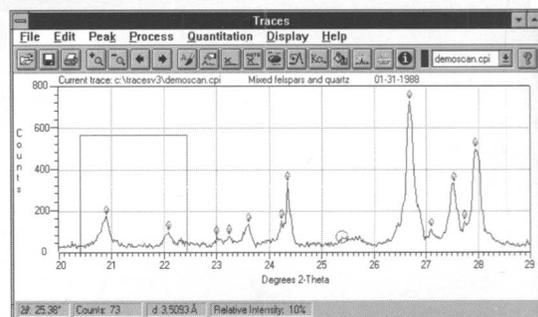
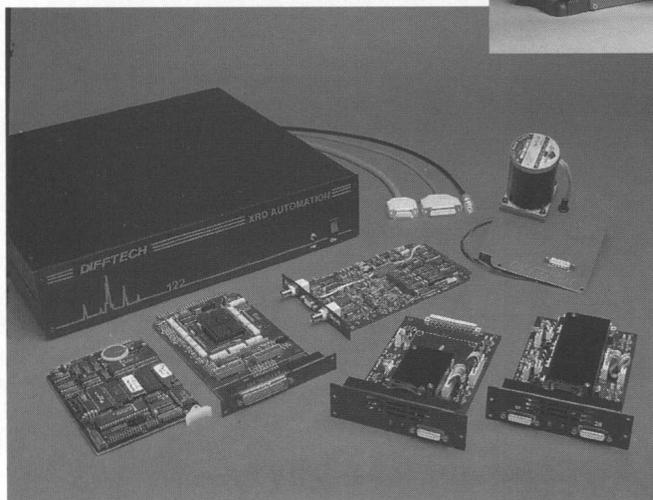
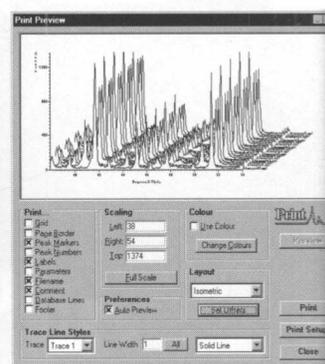
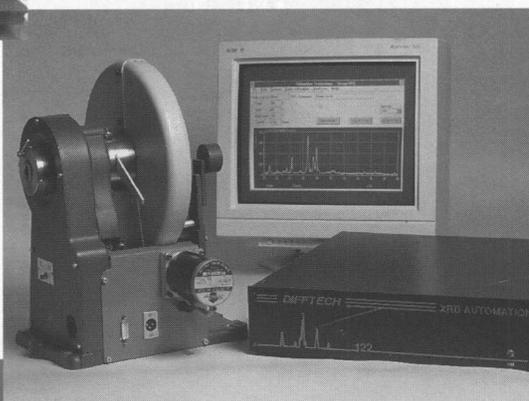


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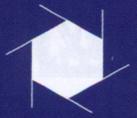
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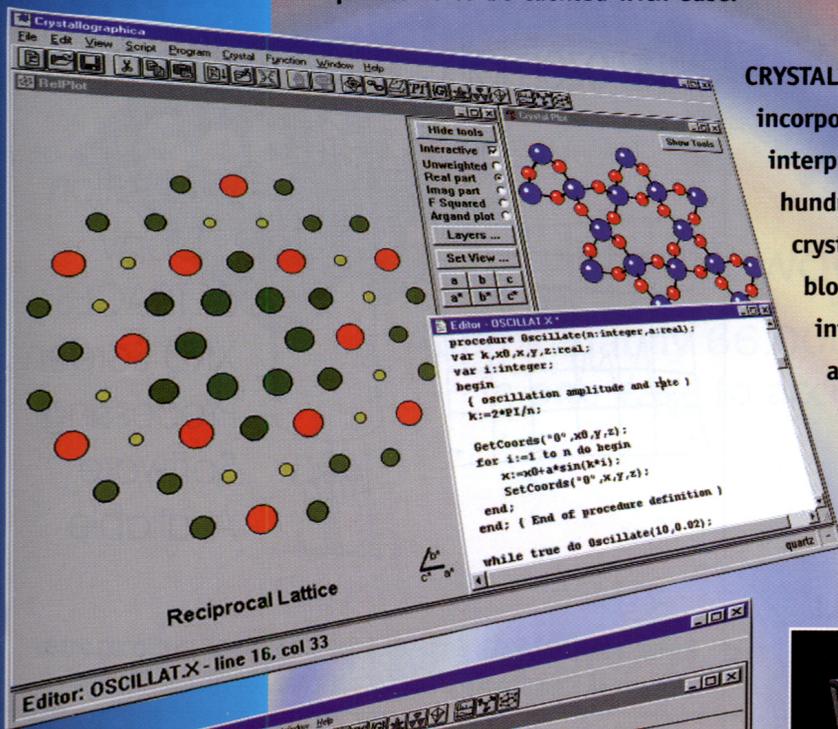
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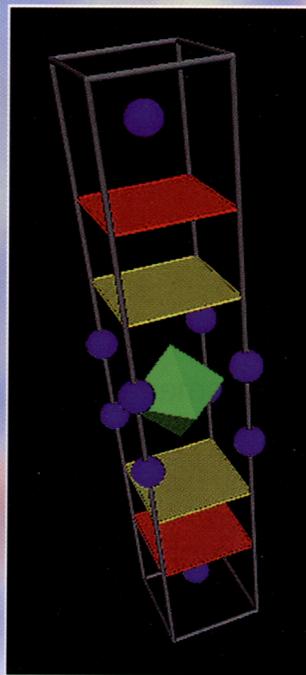
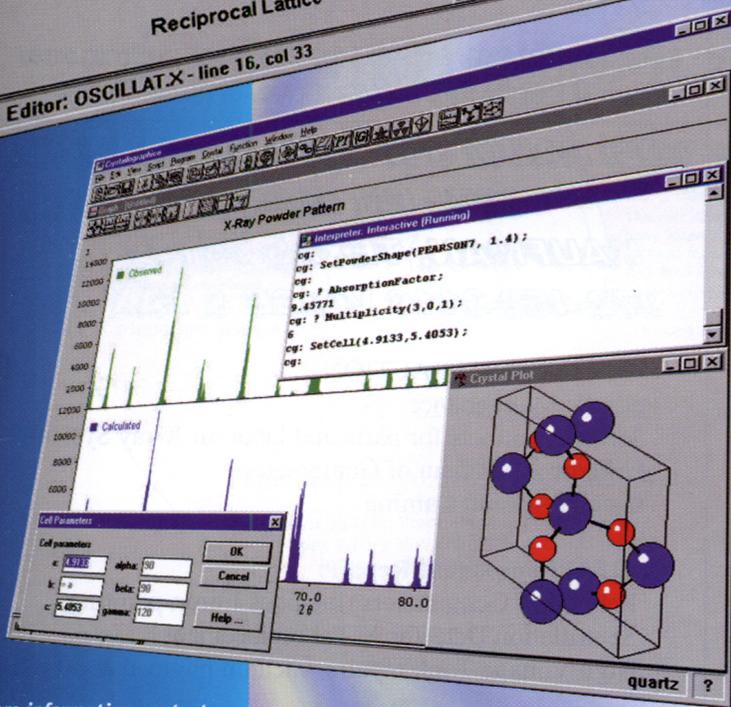


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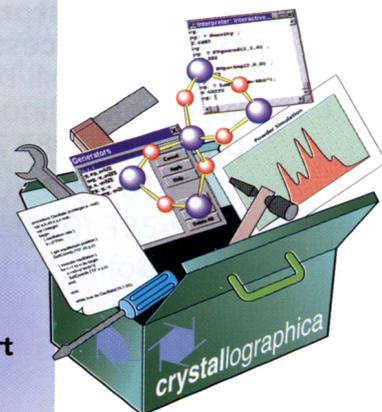
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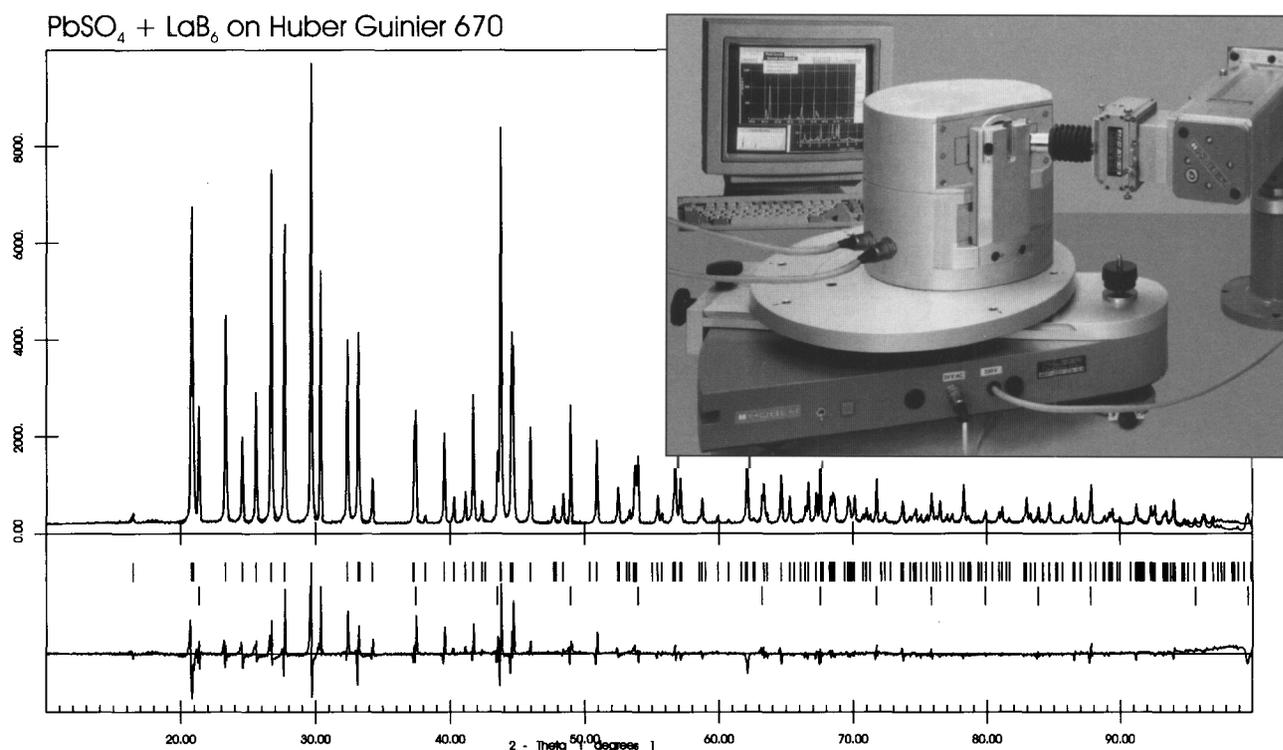
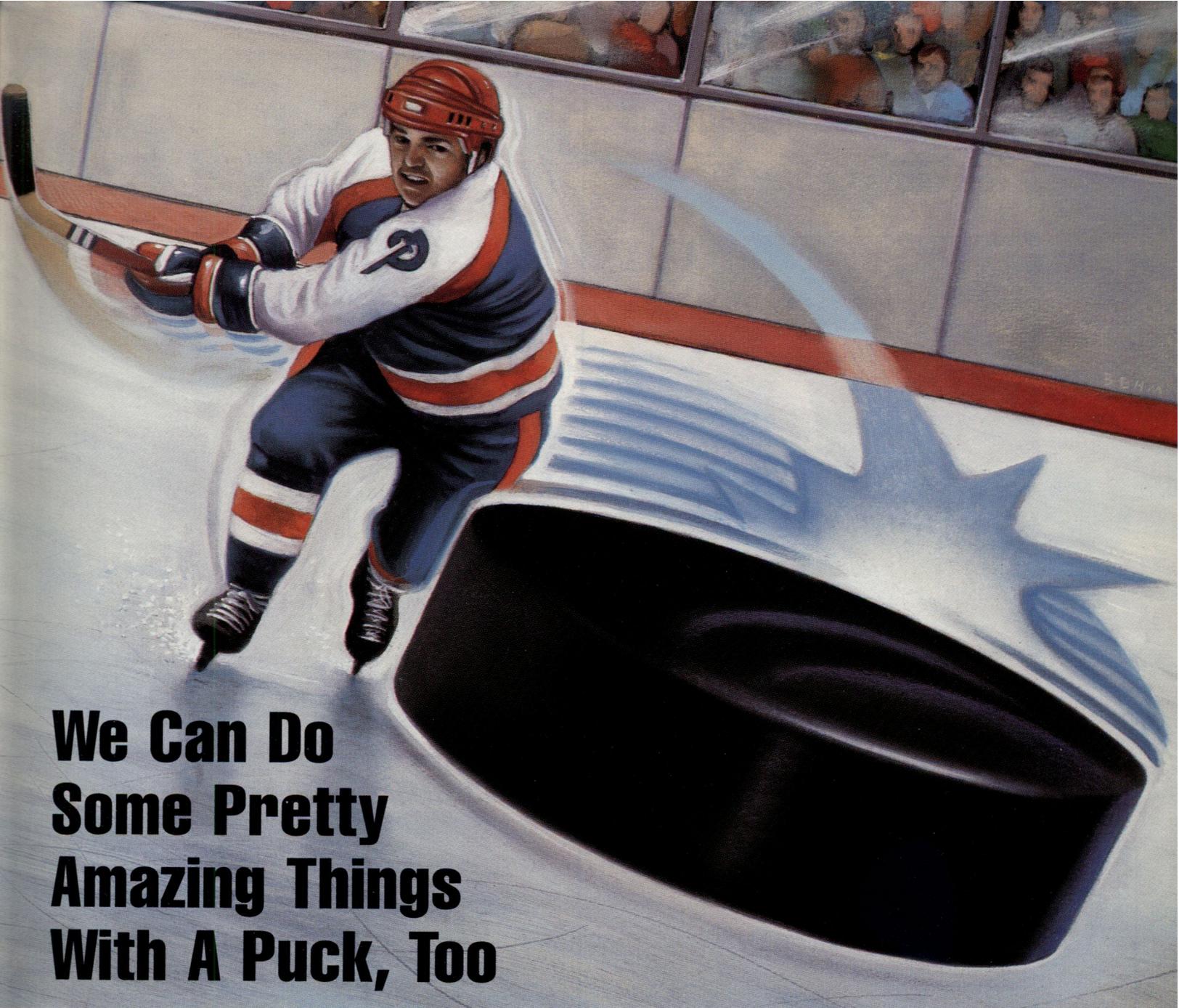


IMAGE PLATE GUINIER CAMERA 670

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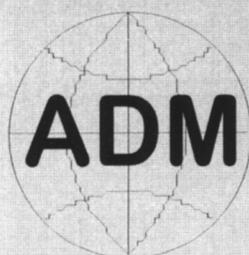
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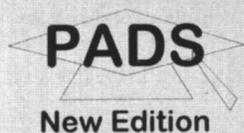
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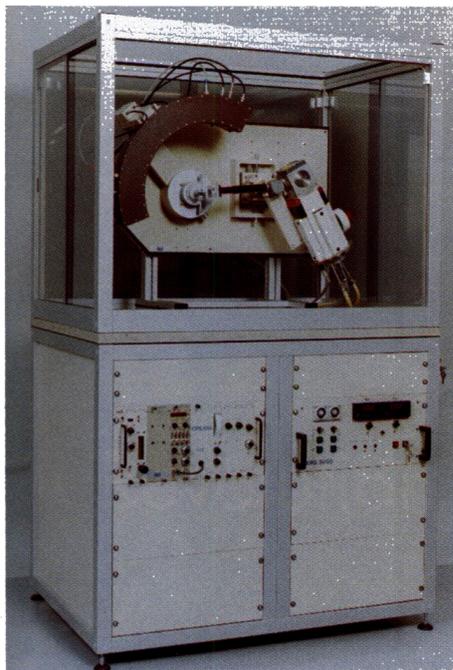


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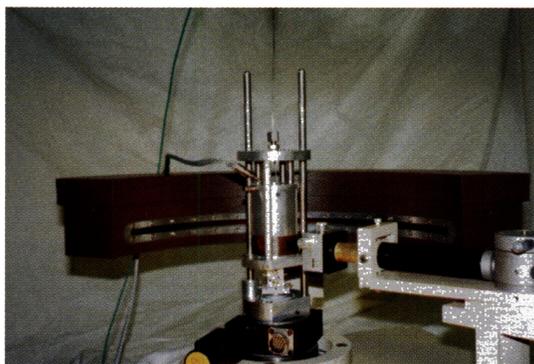
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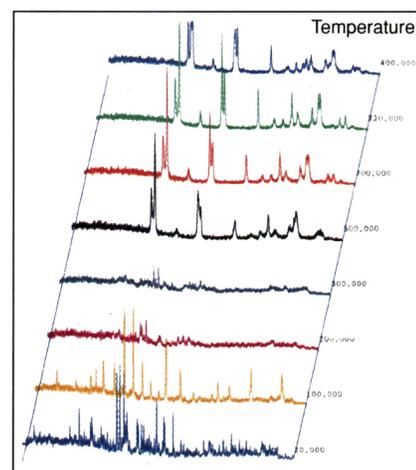
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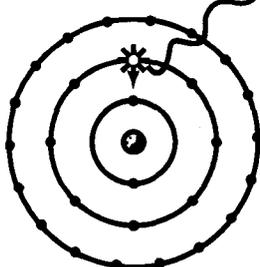
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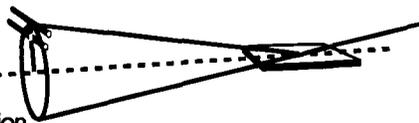
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For further information, please contact:

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